

Group Art Unit: 2886
Confirmation No.: 3799
Examiner: Nur, A.

Atty. Ref.: F04-018US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Tohru Koike et al.
Appl. No. : 10/575,714
Filed : May 8, 2006
For : METHOD FOR MEASURING A SURFACE PLASMON RESONANCE AND NOBLE METAL COMPOUND USED FOR THE SAME

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

THIRD INFORMATION DISCLOSURE STATEMENT

Sir:

The above-identified U.S. patent application corresponds to Japanese Patent Appl. No. JP2006-058217. An Office Action was issued in connection with the Japanese application and a copy of that Office Action is attached. The Japanese Examiner cited WO2005/38442 and JP2006-53036 as being relevant. These two references have been listed on the attached copy of Form PTO/SB/08A. WO2005/38442 was published in the Japanese language. However, that reference corresponds to EP1674857. The European equivalent of the WIPO publication also has been listed on the attached copy of the Form PTO/SB/08A and copies of both of these references are attached. The JP2006-53036 reference does not appear to have an English language equivalent. However, that reference is attached along with an English language abstract obtained from the database of the Japanese Patent Office.

The Examiner is requested to consider these references during the examination and to make the references of record.

Respectfully submitted,



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Date: January 11, 2010